



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION  (PTO-1449)			ATTY. DOCKET NO. <b>060188-0730</b>		SERIAL NO. <b>10/735,688</b>	
			APPLICANT <b>Masayuki ENDO, et al.</b>			
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<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US				
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
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<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
/CS/		T. A. BRUNNER. "High NA lithographic imagery at Brewster's angle". Optical Microlithography XV, Proceedings of SPIE, 2002, 1-9, Vol 4691.				
/CS/		Japanese Patent Office Notice of Reasons for Rejection, in corresponding Japanese Patent Application No. JP 2003-037917, dated September 19, 2006.				
EXAMINER /Caleen Sullivan/ (03/19/2007)				DATE CONSIDERED		

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